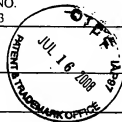


FORM PTO-1449 (Modified)	ATTY. DOCKET NO. P27955	SERIAL NO. 10/538,763
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT: Steven D. SLONAKER et al.	
(Use several sheets if necessary)	FILING DATE: June 10, 2005	GROUP: 2812



REFERENCE DESIGNATION							U.S. PATENT DOCUMENTS	
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)		

FOREIGN PATENT DOCUMENTS								
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
						YES	NO	

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)								
/K.G./		Nakashima, T., "Impact of Zernike cross-term on linewidth control", SPIE Vol. 4691, 2002, July 15, 2002, pages 33-43						
/K.G./		Shiode, Y., "Method of Zernike coefficients extraction for optics aberration", SPIE Vol. 4691, 2002, pages 1453-1464, Abstract (pages 1453), 2.2 Illumination source Design (pages 1454-1455)						
/K.G./		Nakashima, T., "Evaluation of Zernike sensitivity method for CD distribution", SPIE Vol. 5040, 2003, pages 1600-1610						
/K.G./		Slonaker, S., "Further pursuit of correlation between lens aberration content and imaging performance", SPIE Vol. 4346, 2001, pages 1394-1403						
/K.G./		International Search Report (PCT/ISA/210) for International Application No. PCT/US04/04854						

EXAMINER	/Kibrom Gebresilassie/	DATE CONSIDERED	12/17/2008
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.